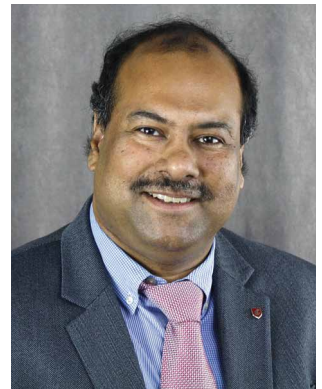


From the EIC

40th IEEE VLSI Test Symposium 2022



■ **THE ARTICLES IN** this issue are divided into two groups: 1) the first group comprises selected articles from the 40th IEEE VLSI Test Symposium 2022 and 2) the second group consists of general interest articles.

The highlight of this issue is the Special Issue on the 40th IEEE VLSI Test Symposium 2022 (VTS 22). VTS is one of the premier conferences of the VLSI test community. VTS explores emerging trends and novel concepts in the test, validation, yield, reliability, and security of microelectronic circuits and systems. VTS is sponsored by the IEEE Computer Society and the IEEE Test Technology Technical Community (TTTC). Selected authors of VTS 22 were invited to submit extended versions of their articles. Those submitted articles then went through *IEEE Design&Test*'s review process. Finally, we accepted

six articles to be published in the *IEEE Design&Test* special issue. We thank the guest editor Sule Ozev and *IEEE Design&Test* Associate Editor-in-Chief Mehdi Tahoori for making this special issue possible.

In addition, we present in this issue two general interest articles, titled as follows: 1) "Detecting Pediatric Foot Deformities Using Plantar Pressure Measurements: A Semisupervised Approach" and 2) "Building an Open-Source DNA Assembler Device."

Many thanks to Scott Davidson for The Last Byte article titled "Our Gated Community."

I hope you enjoy reading this issue of *IEEE Design&Test*. ■

A handwritten signature in black ink, appearing to read 'P. Pande'.

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